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#### DIFFERENTIAL-TO-LVDS BUFFER/DIVIDER W/INTERNAL TERMINATION

## ICS889875

## **General Description**

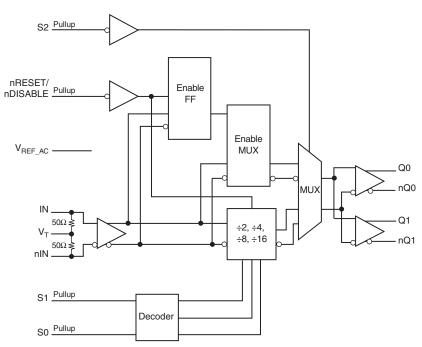


The ICS889875 is a high speed Differential-to-LVDS Buffer/Divider w/Internal Termination and is a member of the HiPerClockS<sup>™</sup> family of high performance clock solutions from IDT. The ICS889875 has a selectable ÷1, ÷2, ÷4, ÷8, ÷16

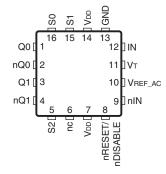
output dividers. The clock input has internal termination resistors, allowing it to interface with several differential signal types while minimizing the number of required external components. The device is packaged in a small, 3mm x 3mm VFQFN package, making it ideal for use on space-constrained boards.

## **Features**

- · Two LVDS outputs
- Frequency divide select options: ÷1, ÷2, ÷4, ÷8, ÷16
- IN, nIN input can accept the following differential input levels: LVPECL, LVDS, CML
- Output frequency: >2GHz
- Cycle-to-cycle jitter: 1ps RMS (maximum)
- Total jitter: 10ps (typical)
- Output skew: 15ps (maximum)
- Part-to-part skew: 280ps (maximum)
- Propagation Delay: 1140ps (maximum)
- Full 2.5V supply mode ٠
- -40°C to 85°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) • packages



## **Pin Assignment**



#### ICS889875

**16-Lead VFQFN** 3mm x 3mm x 0.925mm package body K Package **Top View** 

**Block Diagram** 

## **Table 1. Pin Descriptions**

Number	Name	Т	уре	Description
1, 2	Q0, nQ0	Output		Differential output pair. Divide by 1, 2, 4, 8, or 16. Unused outputs must be terminated with $100\Omega$ across the differential pair. LVDS interface levels.
3, 4	Q1, nQ1	Output		Differential output pair. Divide by 1, 2, 4, 8, or 16. Unused outputs must be terminated with $100\Omega$ across the differential pair. LVDS interface levels.
5, 15, 16	S2, S1, S0	Input	Pullup	Select pins. Internal 37k $\Omega$ pullup resistor. Logic HIGH if left disconnected. Input threshold is V <sub>DD</sub> /2. LVCMOS/LVTTL interface levels.
6	nc	Unused		No connect.
7, 14	V <sub>DD</sub>	Power		Power supply pins.
8	nRESET/ nDISABLE	Input	Pullup	Synchronizing enable/disable pin. When LOW, resets the divider (divided by 1, 2, 4, 8 or 16 mode). When HIGH, disconnected. The reset and disable function occurs on the next high-to-low clock input transition. Input threshold is $V_{DD}/2V$ . Includes a $37k\Omega$ pull-up resistor. LVTTL / LVCMOS interface levels.
9	nIN	Input		Inverting differential LVPECL clock input. $R_T = 50\Omega$ termination to $V_T$ .
10	V <sub>REF_AC</sub>	Output		Reference voltage for AC-coupled applications. Equal to V <sub>DD</sub> – 1.4V (approx.). Maximum sink/source current is 0.5mA.
11	V <sub>T</sub>	Input		Termination center-tap input.
12	IN	Input		Non-inverting LVPECL differential clock input. $R_T = 50\Omega$ termination to V <sub>T</sub> .
13	GND	Power		Power supply ground.

NOTE: Pullup refers to internal input resistors. See Table 2, Pin Characteristics, for typical values.

## **Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
R <sub>PULLUP</sub>	Input Pullup Resistor			37		kΩ

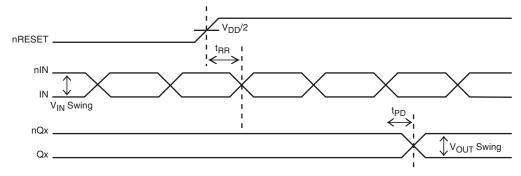
## **Function Tables**

#### Table 3A. Control Input Function Table

Input	Outputs				
nRESET	Q0, Q1 nQ0, nQ1				
0	Disabled; LOW Disabled; H				
1	Enabled	Enabled			

NOTE: After nRESET switches, the clock outputs are disabled or enabled following a falling input clock edge as shown in *Figure 1*.

#### Figure 1. nRESET Timing Diagram



#### Table 3B. Truth Table

	Inputs	Outputs		
nRESET/nDISABLE	S2	S1	S0	Q0/nQ0, Q1/nQ1
1	0	Х	Х	Reference Clock (pass through)
1	1	0	0	Reference Clock ÷2
1	1	0	1	Reference Clock ÷4
1	1	1	0	Reference Clock ÷8
1	1	1	1	Reference Clock ÷16
0 (NOTE 1)	Х	Х	Х	Qx = LOW, nQx = HIGH; Clock disabled

NOTE 1: Reset/disable function is asserted on the next clock input (IN/nIN) high-to-low transition.

## **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>DD</sub>	4.6V
Inputs, V <sub>I</sub>	-0.5V to V <sub>DD</sub> + 0.5V
Outputs, I <sub>O</sub> Continuos Current Surge Current	10mA 15mA
Input Current, IN, nIN	±50mA
V <sub>T</sub> Current, I <sub>VT</sub>	±100mA
Input Sink/Source, I <sub>REF_AC</sub>	± 0.5mA
Operating Temperature Range, T <sub>A</sub>	-40°C to +85°C
Package Thermal Impedance, $\theta_{JA}$ , (Junction-to-Ambient)	88.5°C/W (0 mps)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

## **DC Electrical Characteristics**

Table 4A. Power Supply DC Characteristics,  $V_{DD}$  = 2.5V ± 5%,  $T_A$  = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>DD</sub>	Positive Supply Voltage		2.375	2.5	2.625	V
I <sub>DD</sub>	Power Supply Current				82	mA

#### Table 4B. LVCMOS/LVTTL DC Characteristics, $V_{DD} = 2.5V \pm 5\%$ , $T_A = -40^{\circ}C$ to $85^{\circ}C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>IH</sub>	Input High Voltage		2		V <sub>DD</sub> + 0.3	V
V <sub>IL</sub>	Input Low Voltage		0		0.8	V
I <sub>IH</sub>	Input High Current	$V_{DD} = V_{IN} = 2.625V$			5	μA
I <sub>IL</sub>	Input Low Current	$V_{DD} = 2.625V, V_{IN} = 0V$	-150			μA

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
R <sub>IN</sub>	Differential Input Resistance	(IN, nIN)			100		Ω
V <sub>IH</sub>	Input High Voltage	(IN, nIN)		1.2		V <sub>DD</sub> + 0.05	V
V <sub>IL</sub>	Input Low Voltage	(IN, nIN)		0		V <sub>DD</sub> – 0.15	V
V <sub>IN</sub>	Input Voltage Swing			0.15		2.8	V
$V_{DIFF_IN}$	Differential Input Voltage Swing			0.3			V
I <sub>IN</sub>	Input Current	(IN, nIN)				45	mA
$V_{REF}_{AC}$	Bias Voltage				V <sub>DD</sub> – 1.35		V

#### Table 4C. Differential DC Characteristics, $V_{DD} = 2.5V \pm 5\%$ , $T_A = -40^{\circ}C$ to $85^{\circ}C$

#### Table 4D. LVDS DC Characteristics, $V_{DD}$ = 2.5V $\pm$ 5%, $T_{A}$ = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OUT</sub>	Output Voltage Swing		250	350	400	mV
V <sub>OH</sub>	Output High Voltage			1.475		V
V <sub>OL</sub>	Output Low Voltage		0.925			V
V <sub>CCM</sub>	Output Common Mode Voltage			1.35		V
$\Delta V_{OCM}$	Change in Common Mode Voltage				50	mV

## **AC Electrical Characteristics**

#### Table 5. AC Characteristics, $V_{DD}$ = 2.5V $\pm$ 5%, $T_{A}$ = -40°C to 85°C

Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
			÷1, ÷2, ÷4		>2		GHz
f <sub>MAX</sub>	Maximum Input Frequ	lency	÷8, ÷16		>1.5		GHz
t <sub>PD</sub>	Propagation Delay; NOTE 1	IN-to-Q		690		1140	ps
<i>t</i> sk(o)	Output Skew; NOTE 2, 3					15	ps
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 3, 4					280	ps
<i>t</i> jit(cc)	Cycle-to-Cycle Jitter, RMS; NOTE 5					1	ps
<i>t</i> jit(j)	Total Jitter				10		ps
t <sub>RR</sub>	Reset Recovery Time			600			ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	)		70		260	ps

All parameters characterized at  $\ensuremath{\mathsf{f}_{\mathsf{MAX}}}$  unless otherwise noted.

NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at the output differential cross points.

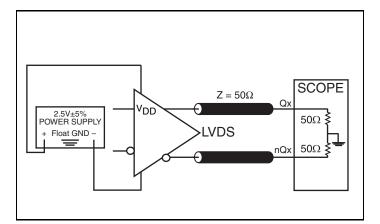
NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at the differential cross points.

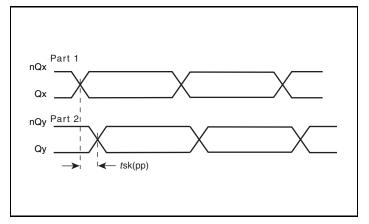
NOTE 5: The cycle-to-cycle jitter on the input will equal the jitter on the output. The part does not add jitter.

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## **Parameter Measurement Information**



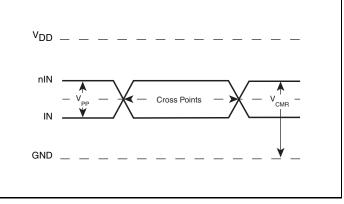
LVDS Output Load AC Test Circuit



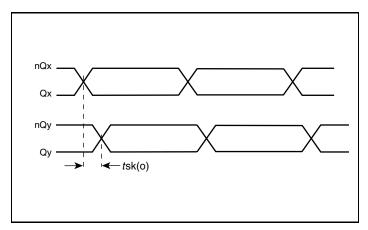
- tcycle n+1

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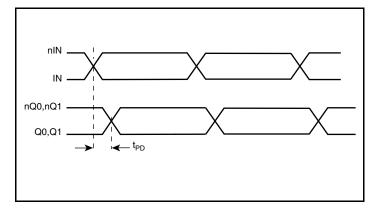
tjit(cc) = |tcycle n – tcycle n+1|1000 Cycles



#### **Differential Input Level**



Output Skew





Cycle-to-Cycle Jitter, RMS

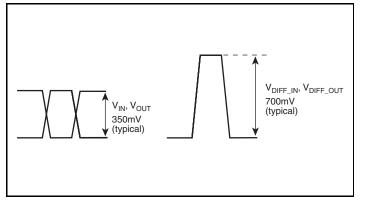
Part-to-Part Skew

nQ0,nQ1

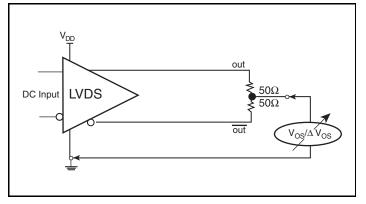
Q0,Q1 -

tcycle n

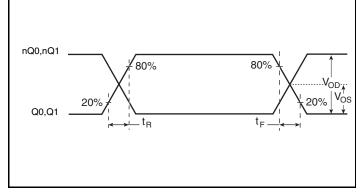
## Parameter Measurement Information, continued



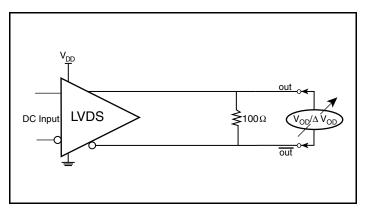
Single-Ended & Differential Input Voltage Swing



Offset Voltage Setup









## **Application Information**

#### Wiring the Differential Input to Accept Single Ended Levels

*Figure 2* shows how the differential input can be wired to accept single ended levels. The reference voltage V\_REF =  $V_{DD}/2$  is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V\_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and  $V_{DD}$  = 3.3V, V\_REF should be 1.25V and R2/R1 = 0.609.

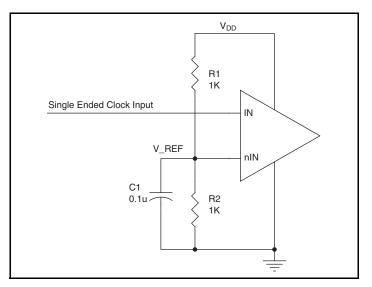


Figure 2. Single-Ended Signal Driving Differential Input

#### **Recommendations for Unused Input Pins**

#### Inputs:

#### **LVCMOS Select Pins**

All control pins have internal pull-ups; additional resistance is not required but can be added for additional protection. A 1k $\Omega$  resistor can be used.

#### **OUTputs:**

#### **LVDS Outputs**

All unused LVDS output pairs can be either left floating or terminated with  $100\Omega$  across. If they are left floating, we recommend that there is no trace attached.

### 2.5V LVPECL Input with Built-In 50 $\Omega$ Termination Interface

The IN /nIN with built-in 50 $\Omega$  terminations accept LVDS, LVPECL, CML, SSTL and other differential signals. Both signals must meet the V<sub>PP</sub> and V<sub>CMR</sub> input requirements. *Figures 3A to 3E* show interface examples for the HiPerClockS IN /nIN with built-in 50 $\Omega$  termination input driven by the most common driver types. The

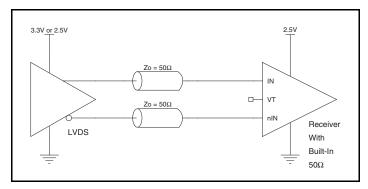


Figure 3A. HiPerClockS IN/nIN Input with Built-In 50  $\Omega$  Driven by an LVDS Driver

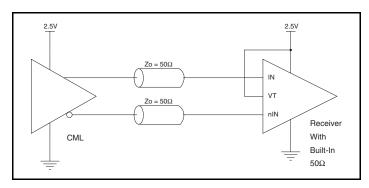


Figure 3C. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$  Driven by a CML Driver

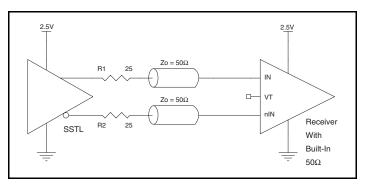


Figure 3E. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$ Driven by an SSTL Driver

input interfaces suggested here are examples only. If the driver is from another vendor, use their termination recommendation. Please consult with the vendor of the driver component to confirm the driver termination requirements.

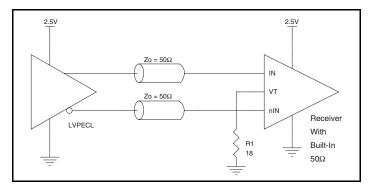


Figure 3B. HiPerClockS IN/nIN Input with Built-In 50  $\Omega$  Driven by an LVPECL Driver

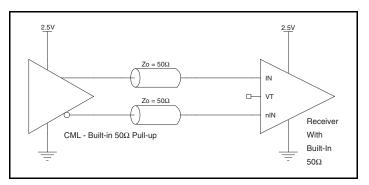


Figure 3D. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$ Driven by a CML Driver with Built-In 50 $\Omega$ Pullup

#### **VFQFN EPAD Thermal Release Path**

In order to maximize both the removal of heat from the package and the electrical performance, a land pattern must be incorporated on the Printed Circuit Board (PCB) within the footprint of the package corresponding to the exposed metal pad or exposed heat slug on the package, as shown in *Figure 4*. The solderable area on the PCB, as defined by the solder mask, should be at least the same size/shape as the exposed pad/slug area on the package to maximize the thermal/electrical performance. Sufficient clearance should be designed on the PCB between the outer edges of the land pattern and the inner edges of pad pattern for the leads to avoid any shorts.

While the land pattern on the PCB provides a means of heat transfer and electrical grounding from the package to the board through a solder joint, thermal vias are necessary to effectively conduct from the surface of the PCB to the ground plane(s). The land pattern must be connected to ground through these vias. The vias act as "heat pipes". The number of vias (i.e. "heat pipes") are

application specific and dependent upon the package power dissipation as well as electrical conductivity requirements. Thus, thermal and electrical analysis and/or testing are recommended to determine the minimum number needed. Maximum thermal and electrical performance is achieved when an array of vias is incorporated in the land pattern. It is recommended to use as many vias connected to ground as possible. It is also recommended that the via diameter should be 12 to 13mils (0.30 to 0.33mm) with 1oz copper via barrel plating. This is desirable to avoid any solder wicking inside the via during the soldering process which may result in voids in solder between the exposed pad/slug and the thermal land. Precautions should be taken to eliminate any solder voids between the exposed heat slug and the land pattern. Note: These recommendations are to be used as a guideline only. For further information, please refer to the Application Note on the Surface Mount Assembly of Amkor's Thermally/Electrically Enhance Leadfame Base Package, Amkor Technology.

transmission line environment. For buffer with multiple LDVS driver.

it is recommended to terminate the unused outputs.

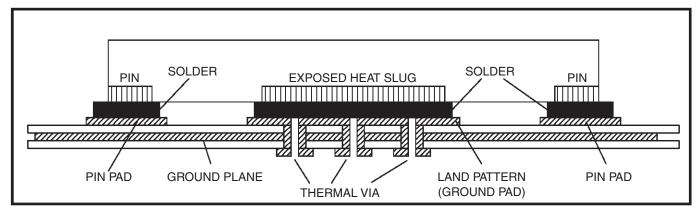


Figure 4. P.C. Assembly for Exposed Pad Thermal Release Path – Side View (drawing not to scale)

#### 2.5V LVDS Driver Termination

Figure 5 shows a typical termination for LVDS driver in characteristic impedance of  $100\Omega$  differential ( $50\Omega$  single)

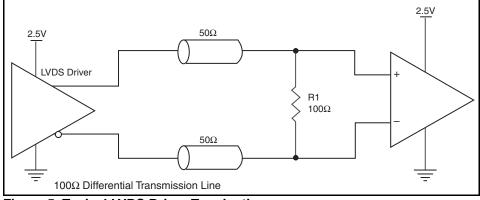


Figure 5. Typical LVDS Driver Termination

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#### **Schematic Example**

Figure 6 shows a schematic example of the ICS889875. This schematic provides examples of input and output handling. The ICS889875 input has built-in 50 $\Omega$  termination resistors. The input can directly accept various types of differential signals without AC coupling. For AC coupling termination, the ICS889875 also provides the V<sub>REF\_AC</sub> pin for proper offset bias. This example

shows the ICS889875 input driven by a 2.5V LVPECL driver. The ICS889875 outputs are LVDS drivers. In this example, we assume the traces are long transmission lines and the receivers of the LVDS drivers have high input impedance without built-in termination.

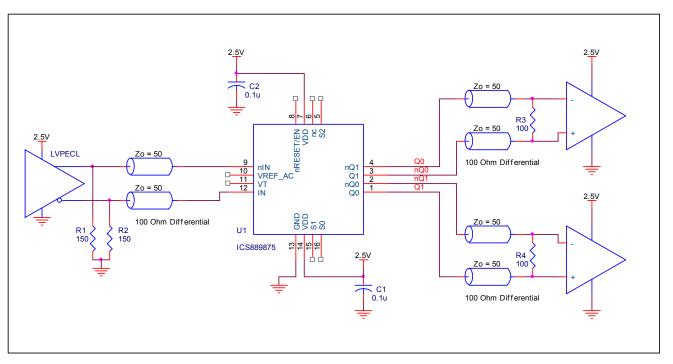


Figure 6. ICS889875 Schematic Example

## **Power Considerations**

This section provides information on power dissipation and junction temperature for the ICS889875. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS889875 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 2.5V + 5\% = 2.625V$ , which gives worst case results.

• Power\_MAX = V<sub>DD MAX</sub> \* I<sub>DD MAX</sub> = 2.625V \* 82mA = **215.25mW** 

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C.

The equation for Tj is as follows: Tj =  $\theta_{JA} * Pd_{total} + T_{A}$ 

Tj = Junction Temperature

 $\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

 $T_{A}$  = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 51.5°C/W per Table 6 below.

Therefore, Tj for an ambient temperature of 85°C with all outputs switching is:

 $85^{\circ}C + 0.215W * 88.5^{\circ}C/W = 104^{\circ}C$ . This is well below the limit of  $125^{\circ}C$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (single layer or multi-layer).

#### Table 6. Thermal Resistance $\theta_{JA}$ for 16 Lead VFQFN, Forced Convection

θ <sub>JA</sub> by Velocity					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	88.5°C/W	77.3°C/W	69.4°C/W		

#### **Reliability Information**

#### Table 7. $\theta_{\text{JA}}$ vs. Air Flow Table for a 16 Lead VFQFN

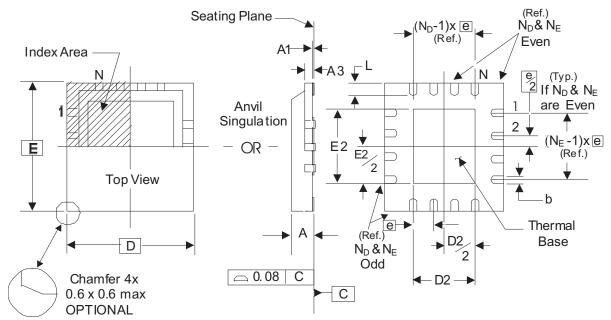
θ <sub>JA</sub> by Velocity					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	88.5°C/W	77.3°C/W	69.4°C/W		

#### **Transistor Count**

The transistor count for ICS889875 is: 328 Pin compatible with SY89875U

## Package Outline and Package Dimensions

#### Package Outline - K Suffix for 16 Lead VFQFN



#### **Table 8. Package Dimensions**

JEDEC Variation: VEED-2/-4 All Dimensions in Millimeters					
Symbol	Minimum	Maximum			
N	16				
Α	0.80	1.00			
A1	0	0.05			
A3	0.25 Ref.				
b	0.18	0.30			
N <sub>D</sub> & N <sub>E</sub>	4				
D & E	3.00 Basic				
D2 & E2	1.00	1.80			
е	0.50 Basic				
L	0.30	0.50			

Reference Document: JEDEC Publication 95, MO-220

IDT™ / ICS™ LVDS BUFFER/DIVIDER W/INTERNAL TERMINATION

## **Ordering Information**

#### **Table 9. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
889875AK	875A	16 Lead VFQFN	Tube	-40°C to 85°C
889875AKT	875A	16 Lead VFQFN	2500 Tape & Reel	-40°C to 85°C
889875AKLF	75AL	"Lead-Free" 16 Lead VFQFN	Tube	-40°C to 85°C
889875AKLFT	75AL	"Lead-Free" 16 Lead VFQFN	2500 Tape & Reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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## **Revision History Sheet**

Rev	Table	Page	Description of Change	Date
В	T4C	5	Differential DC Characteristics Table - corrected typo for V <sub>IH</sub> max. from V <sub>DD</sub> – 0.05V to V <sub>DD</sub> + 0.05V.	7/1/08
В	T1	2	Pin Description Table - deleted "Leave pin floating." from VT pin description.	7/3/08

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